

<b>Notice of References Cited</b>	Application/Control No. 10/516,818	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner David M. Naff	Art Unit 1657	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,947,840	08-1990	Yannas et al.	602/50
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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